

# ACCURATE INDOOR DATA FOR ENERGY RATING



J. Hohl-Ebinger, I. Geisemeyer, B. Müller, C. Reise, A. Schmid

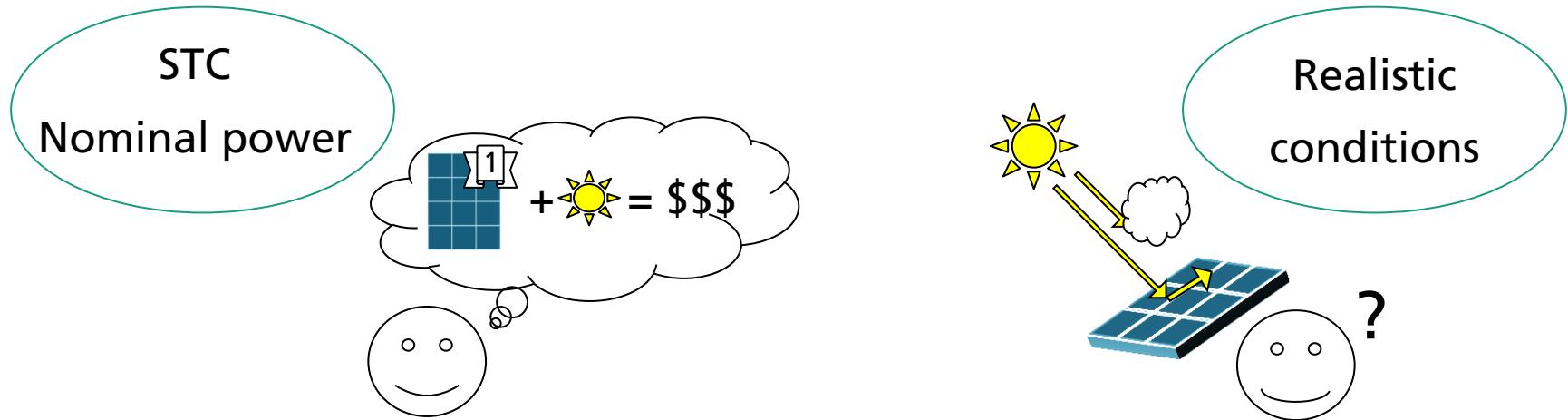
Fraunhofer Institute for Solar Energy Systems ISE

PVPMC Workshop

Supsi Canobbio-Lugano,  
31.03.2017

[www.ise.fraunhofer.de](http://www.ise.fraunhofer.de)

# PV MODULE RATINGS



- Standardized testing for energy rating (e.g. IEC 61853)
  - Angle-of-incidence (AOI) effects
  - Spectral response
  - Absolute module temperature
  - Irradiance and temperature coefficients

# OUTLINE

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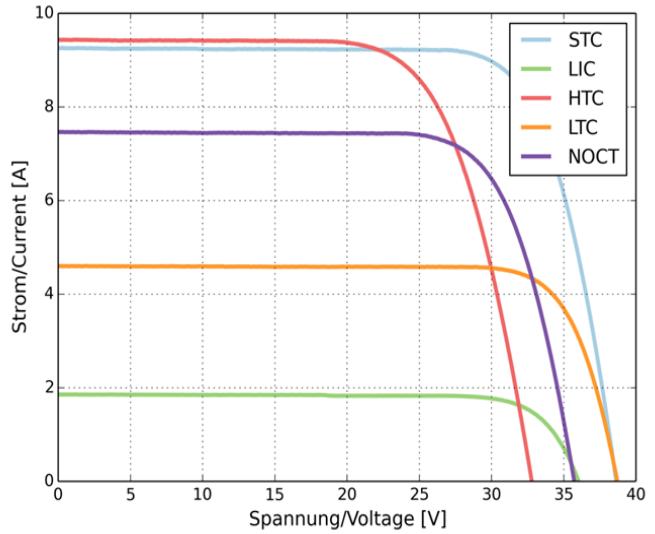
- PV Modules
  - Irradiance and temperature coefficients
  - Angle-of-incidence (AOI) measurement
  
- PV Cells (Lower the uncertainty)
  - Temperature coefficients
  - Angle-of-incidence (AOI) measurement -  
A Study on front texturization

# Characterization of PV Modules

## Power Rating measurements in accordance to IEC 61853

- Power Rating Matrix:
  - mandatory (dark green)
  - at CalLab PV Modules (light green)
  - on request (grey)

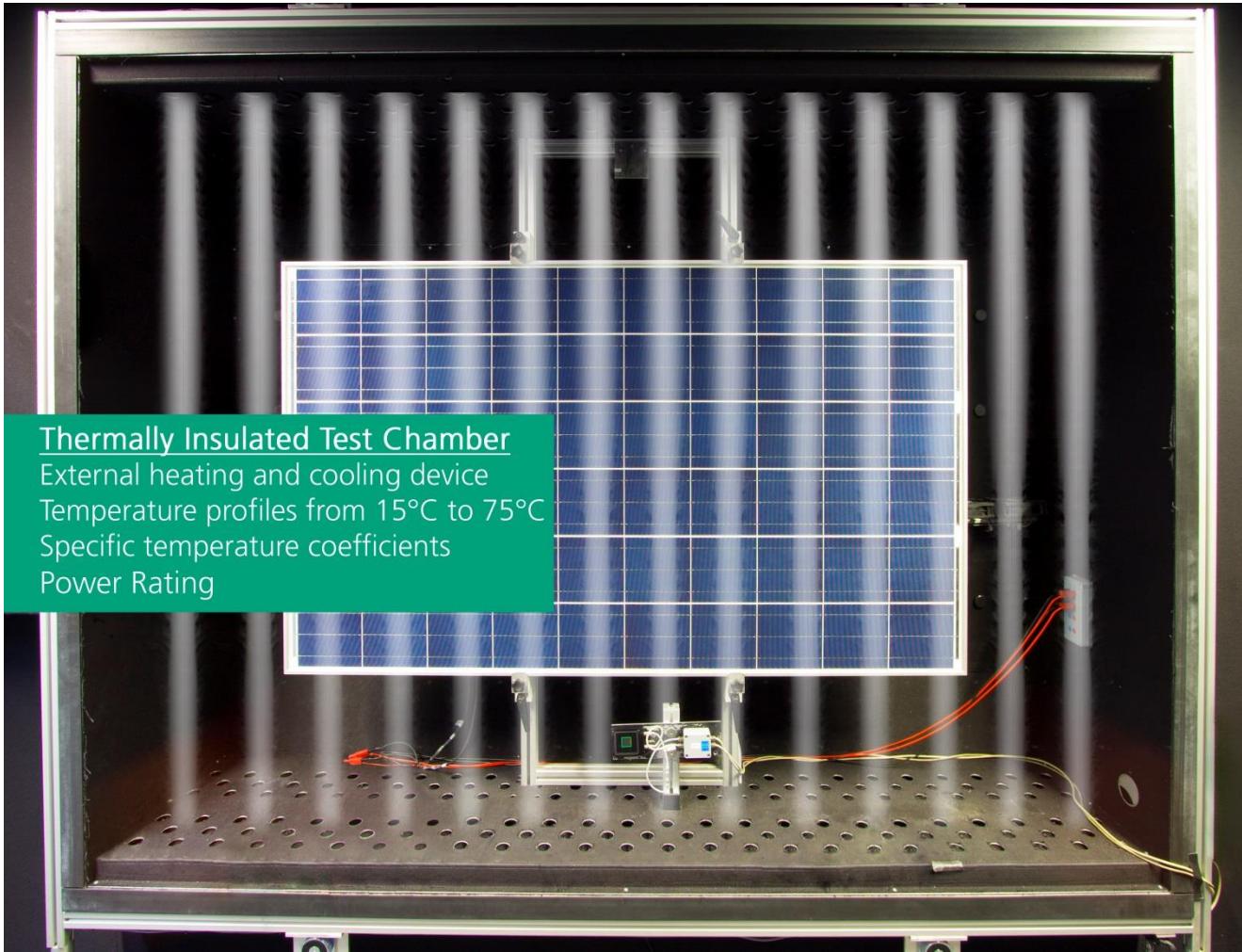
Temperature in °Ct Irradiance in W/m <sup>2</sup> ↓	15	25	NOCT	50	75
1100					
1000 (incl. TC)		STC		HTC	
900					
800		NOCT			
700					
600					
500	LTC				
400					
300					
200	LIC				
100					



- CalLab PV Modules:  
 $I/V(T)$  15-75°C in 1K steps

# Characterization of PV Modules

## Power Rating measurements in accordance to IEC 61853



# Characterization of PV Modules

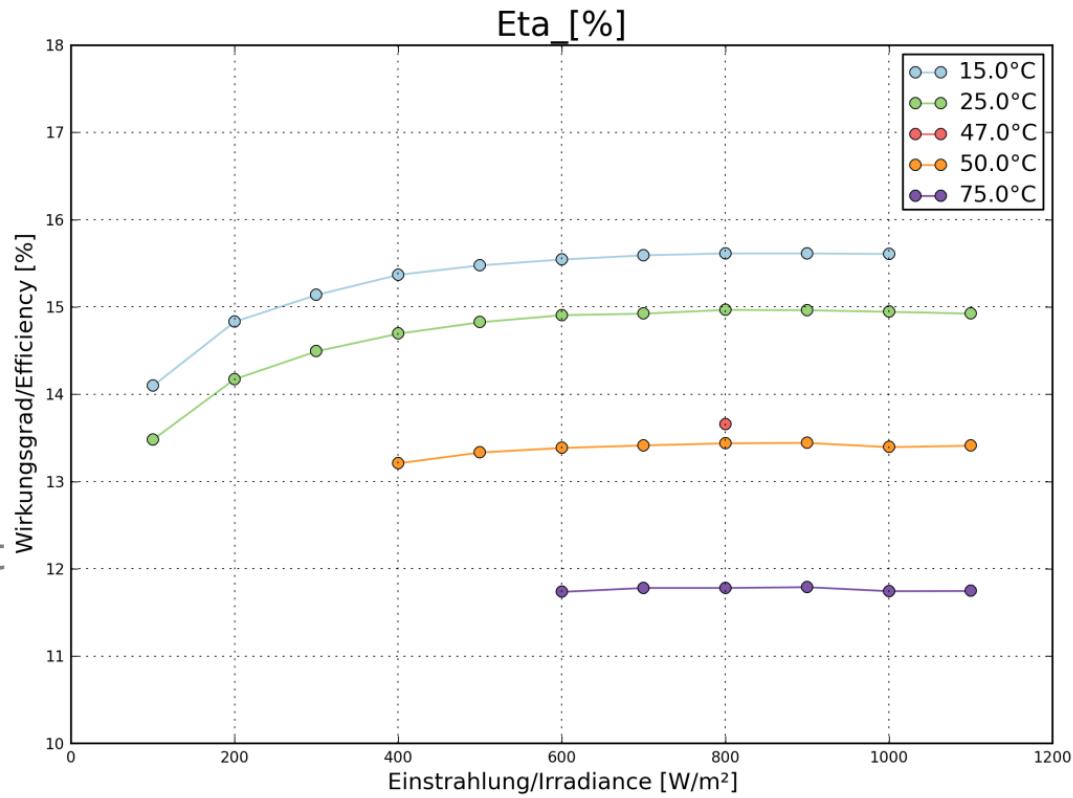
## Power Rating measurements in accordance to IEC 61853

Power Rating is characterization of modules by ...

...determination of the irradiance dependency

...evaluation of the temperature coefficients

...determination of incident angle dependency



# Characterization of PV Modules

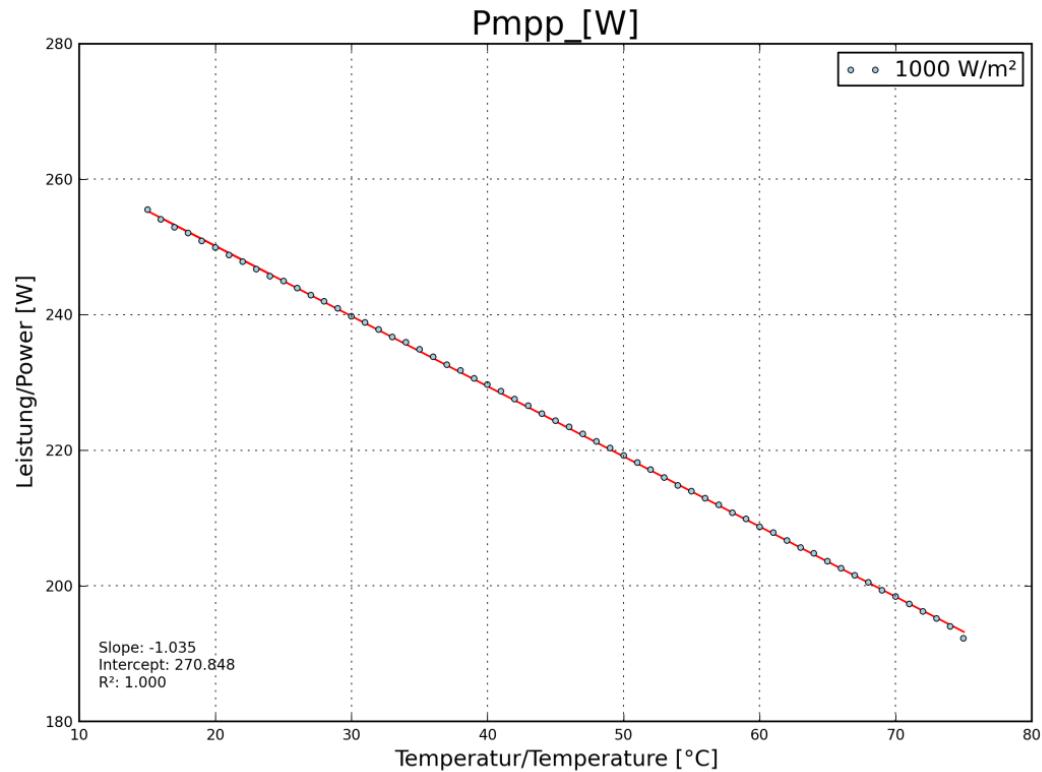
## Power Rating measurements in accordance to IEC 61853

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# Characterization of PV Modules

## Power Rating measurements in accordance to IEC 61853

**Power Rating is characterization of modules by ...**

...determination of the  
irradiance dependency

...evaluation of the  
temperature coefficients

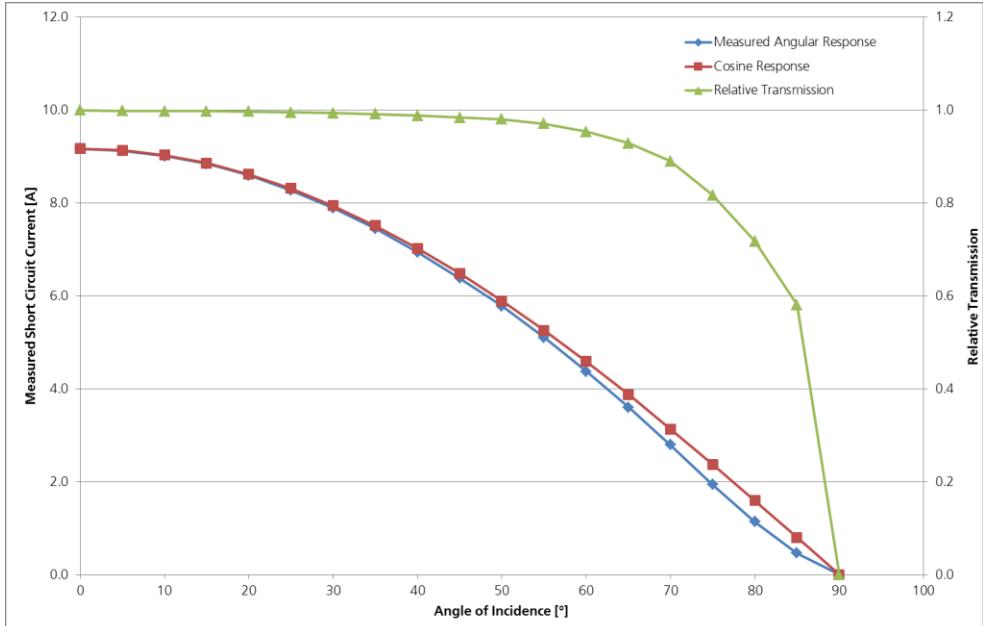
**...determination of incident  
angle dependency**



# Characterization of PV Modules

## Angular Response Measurement

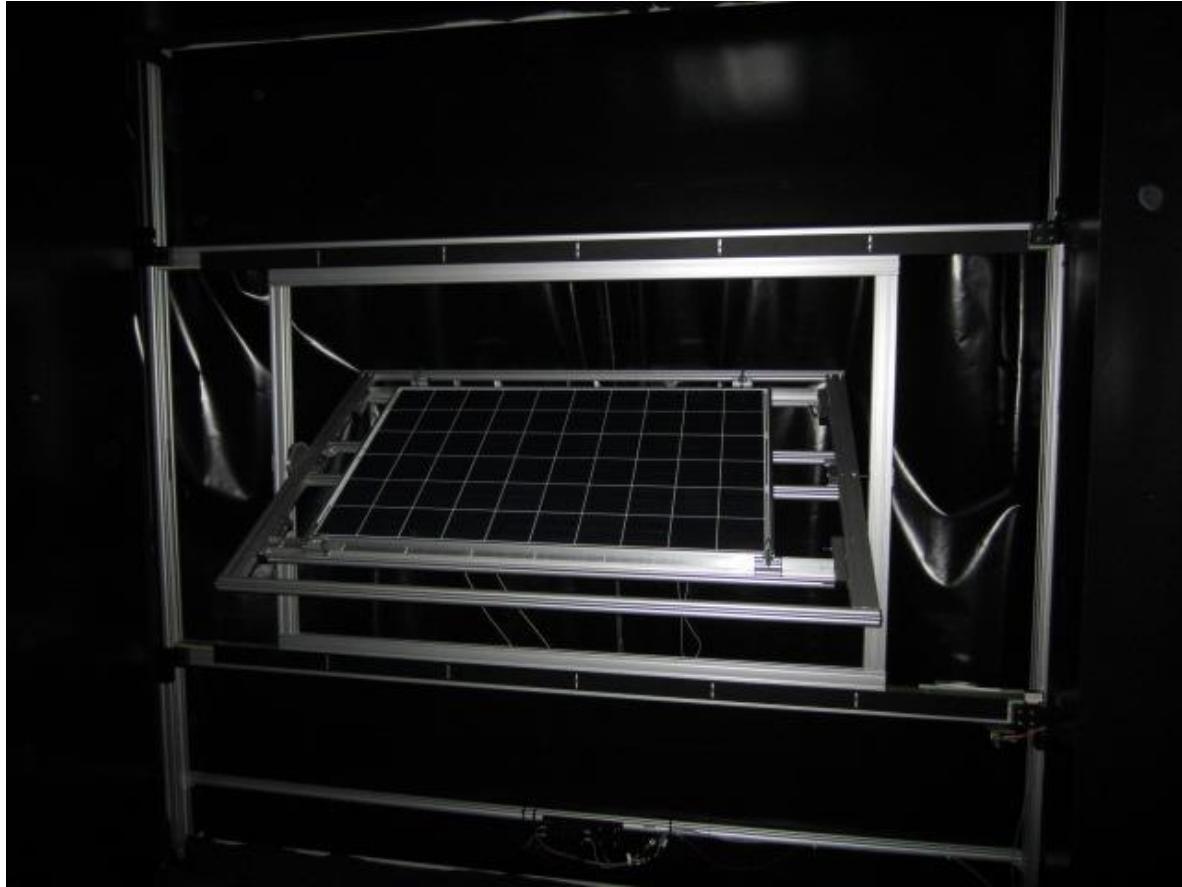
- Part of standard IEC 61853-2
- Test set up to rotate module in fixed steps (~7° increments)
- Measurement on one single cell, either with electrical connection or by shading this cell
- Measured short circuit current is normalized to relative transmittance  $\tau(AOI)$ , which is the „incidence angle modifier (IAM)“ used e. g. in PVsyst



Measured and normalized angular response of a typical PV module

# Characterization of PV Modules

## Angular Response Measurement



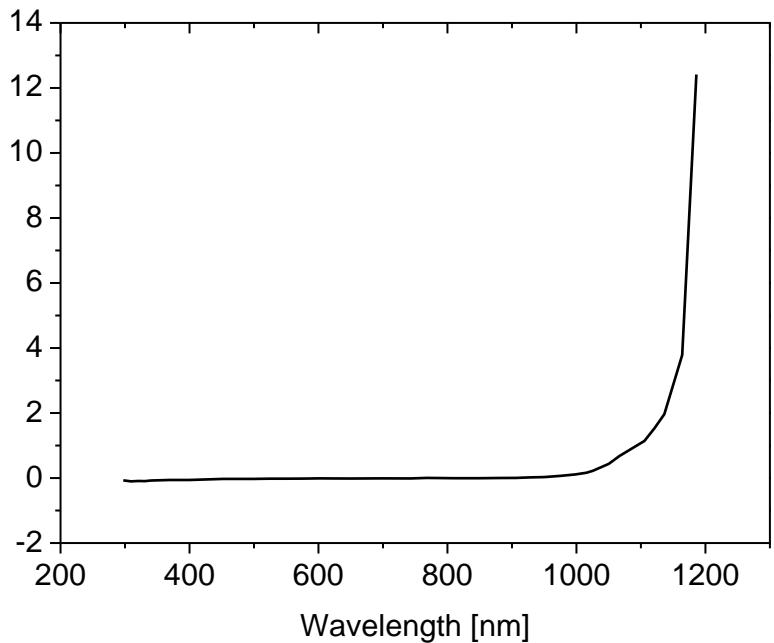
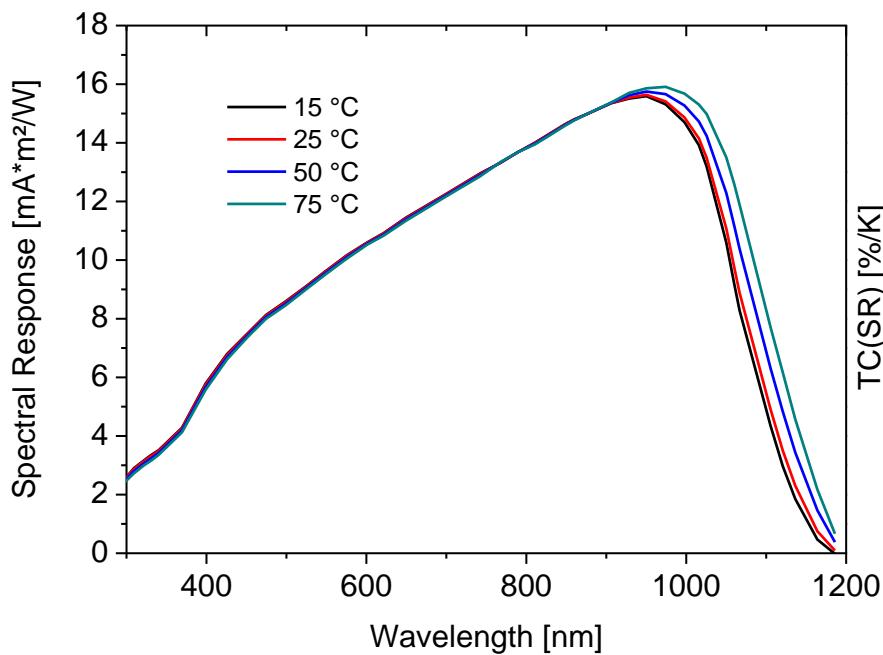
View from inside of  
the simulator on the  
tilted module

# OUTLINE

- PV Modules
  - Irradiance and temperature coefficients
  - Angle-of-incidence (AOI) measurement
- PV Cells (Lower the uncertainty)
  - Temperature coefficients
  - Angle-of-incidence (AOI) measurement -  
A Study on front texturization

# Temperature Coefficient Determination on Cells

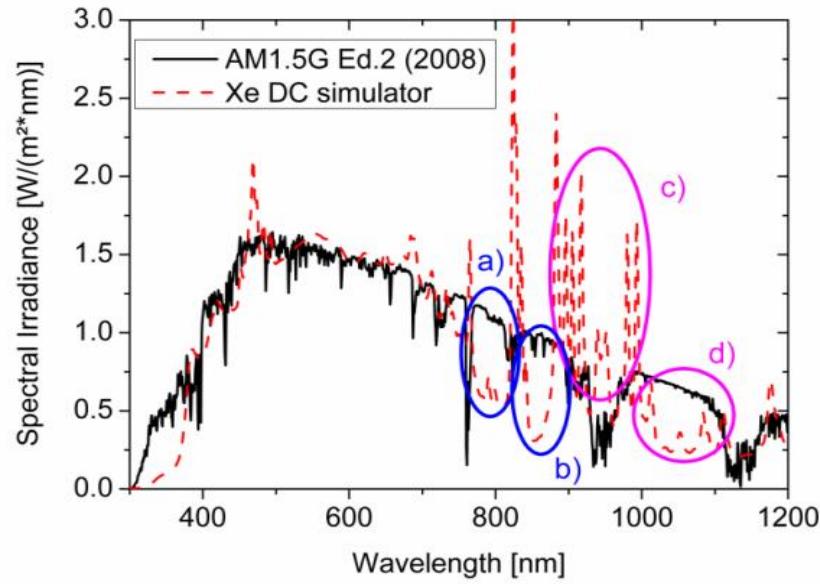
## T-Dependent Spectral Response



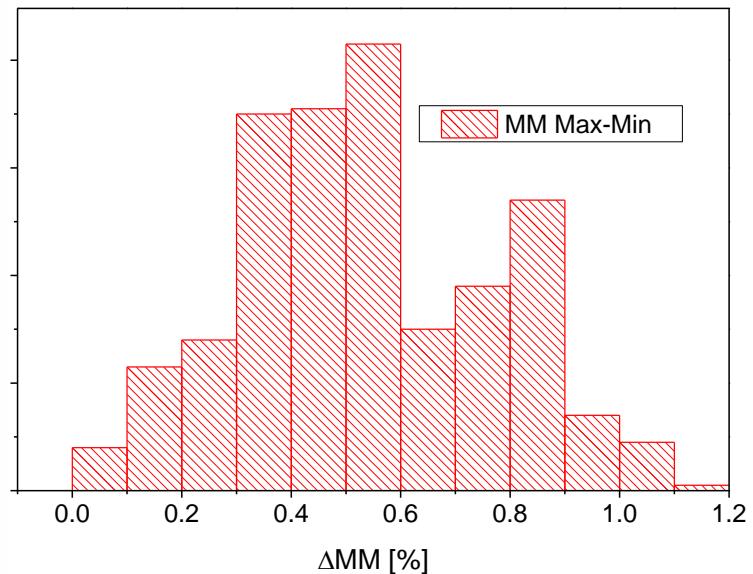
# Temperature Coefficient Determination on Cells

## T-Dependent Spectral Mismatch

■ Class A Simulator Spectrum



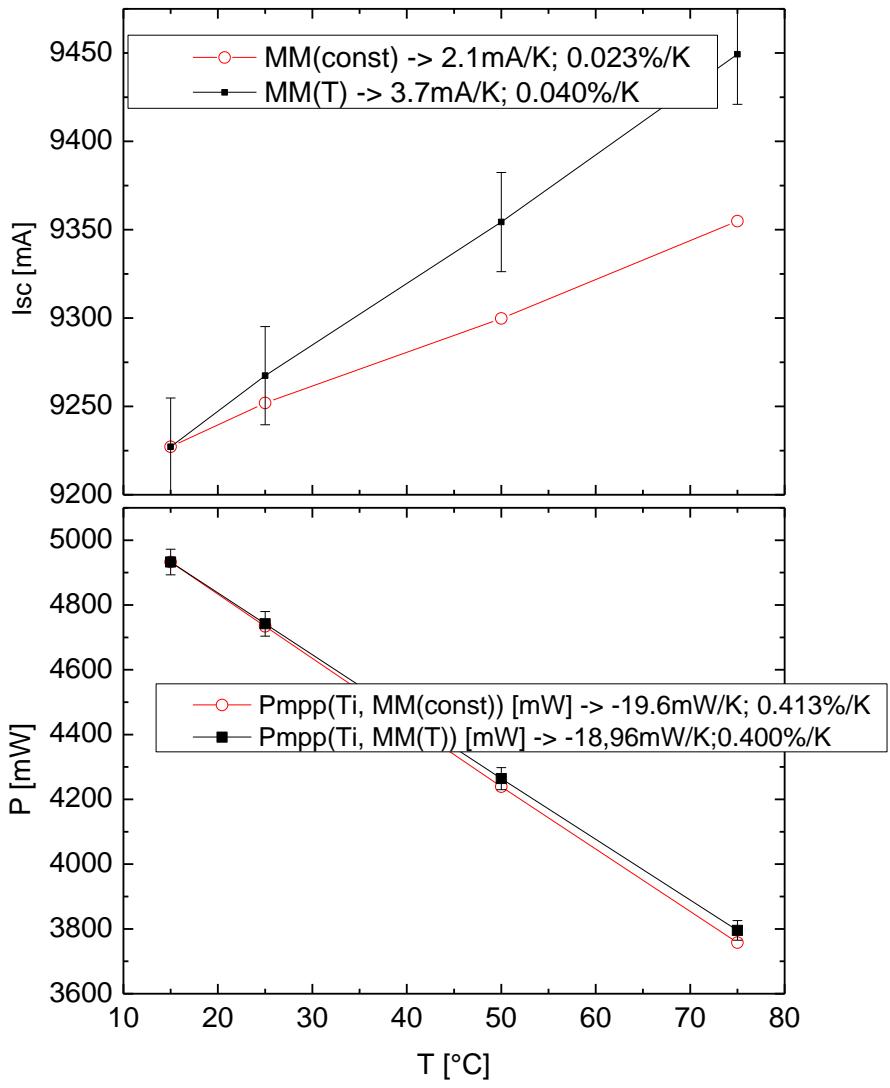
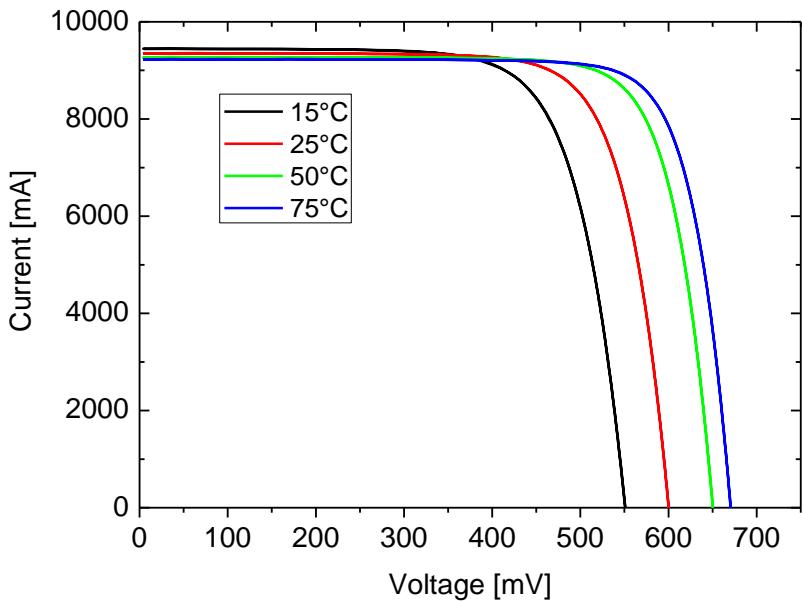
■ MM Change ( $T 15^\circ\text{C} \rightarrow 75^\circ\text{C}$ )



# Temperature Coefficient Determination on Cells

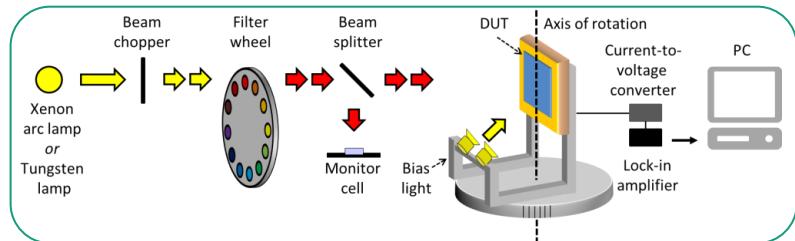
## MM(T) vs MM(const)

- Assumption: 1% MM Change  
(T 15°C->75°C)

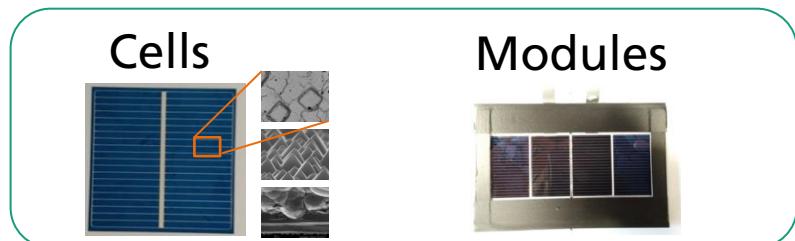


# Texturization Study

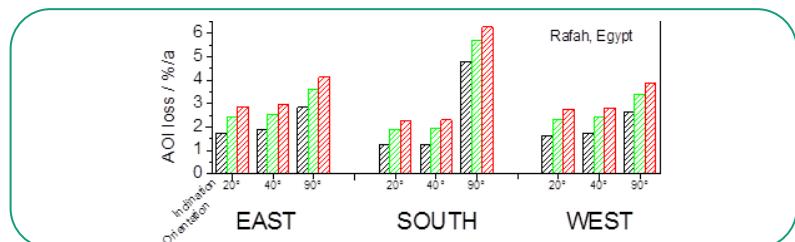
- Angular spectral response
  - Measurement setup
  - Uncertainty analysis



- Test samples (cells & modules)
  - Different front surface textures



- Energy rating



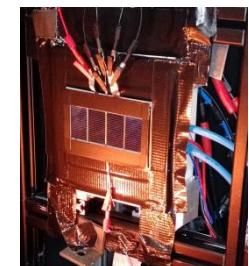
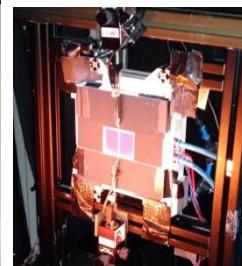
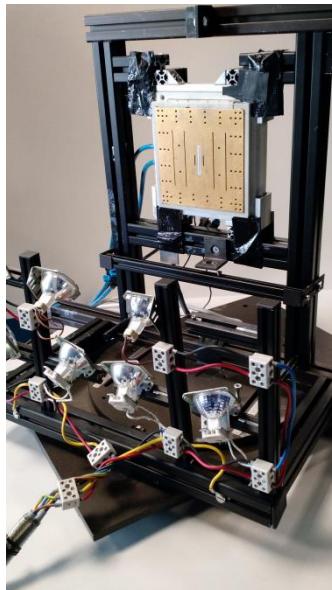
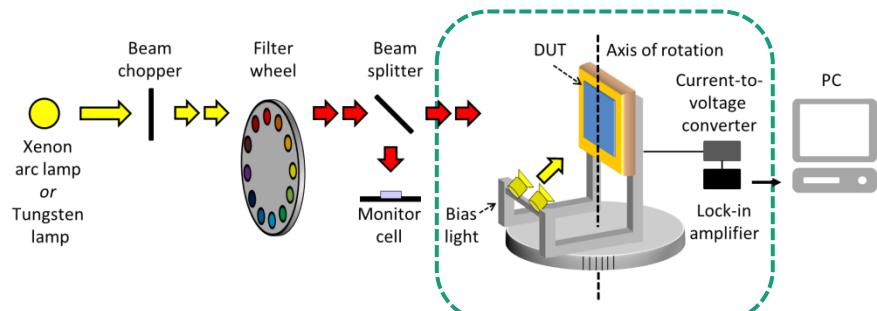
# Measurement of AOI Effects

## Integral vs. Spectrally Resolved

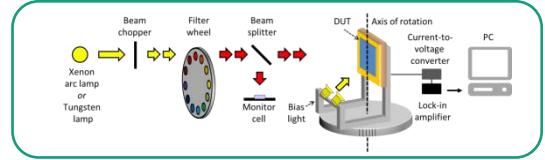
- Why spectrally resolved?
  - Understand differences
  - Validate simulation models
  - Low measurement uncertainty

# Angular Spectral Response (SR) Measurement Setup

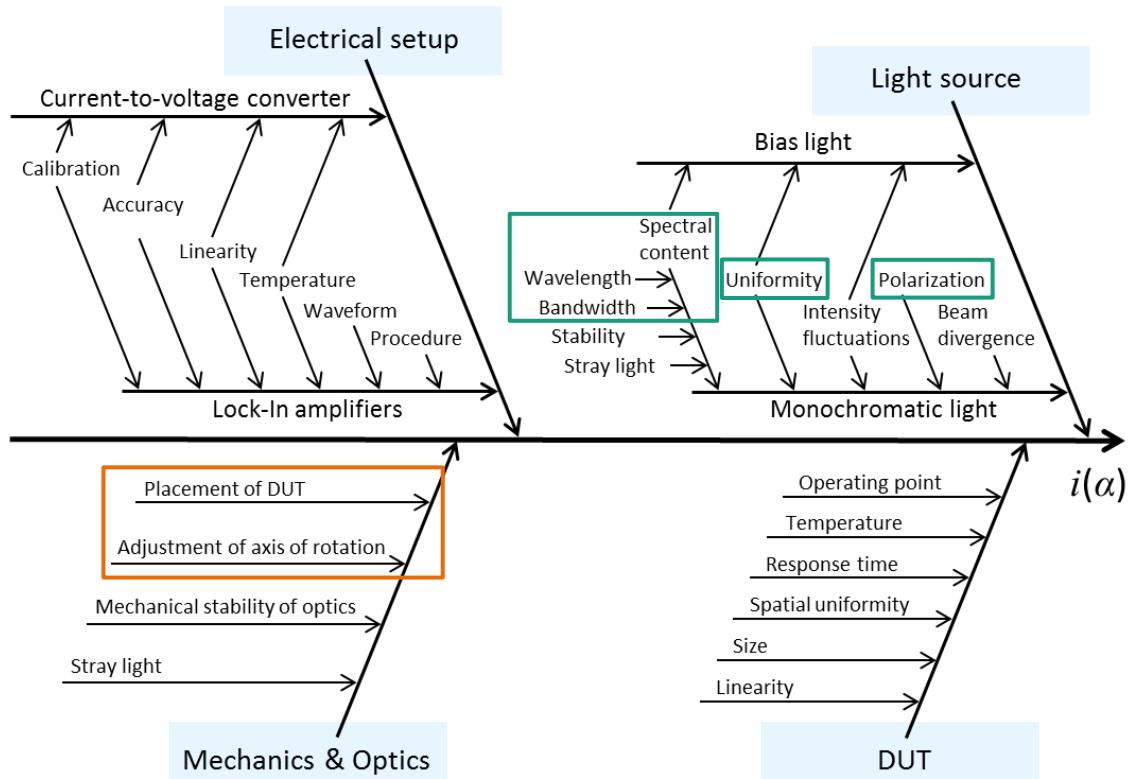
- Filter monochromator
  - Two light sources
  - Lock-in procedure
  - Fully illuminated sample
- Rotary measurement unit
  - T-control
  - Rotating bias light
    - Separates injection-dep.
  - One axis of rotation



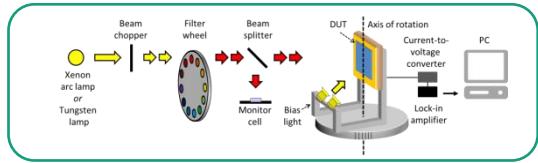
# Angular Spectral Response (SR) Uncertainty Analysis



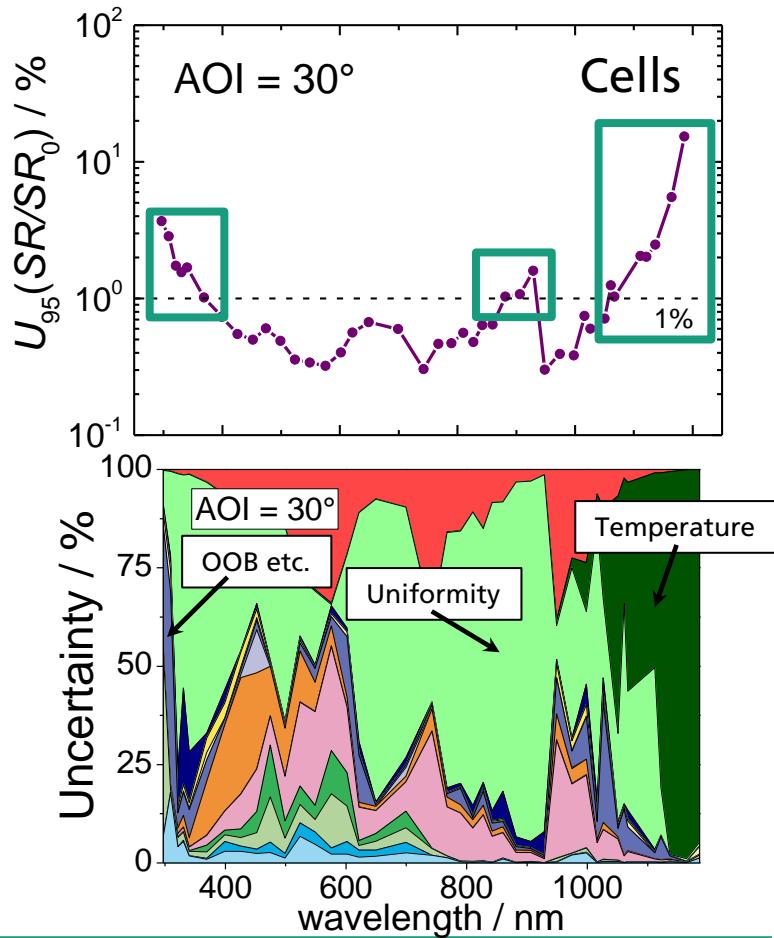
- Based on measured data
  - Spectral content
  - Polarization
  - Uniformity
  - Angular response of different cells and modules



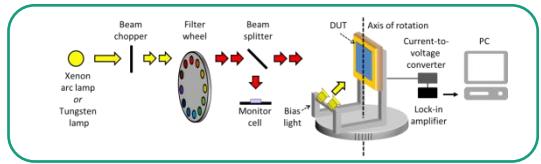
# Change in Angular SR Uncertainty Analysis



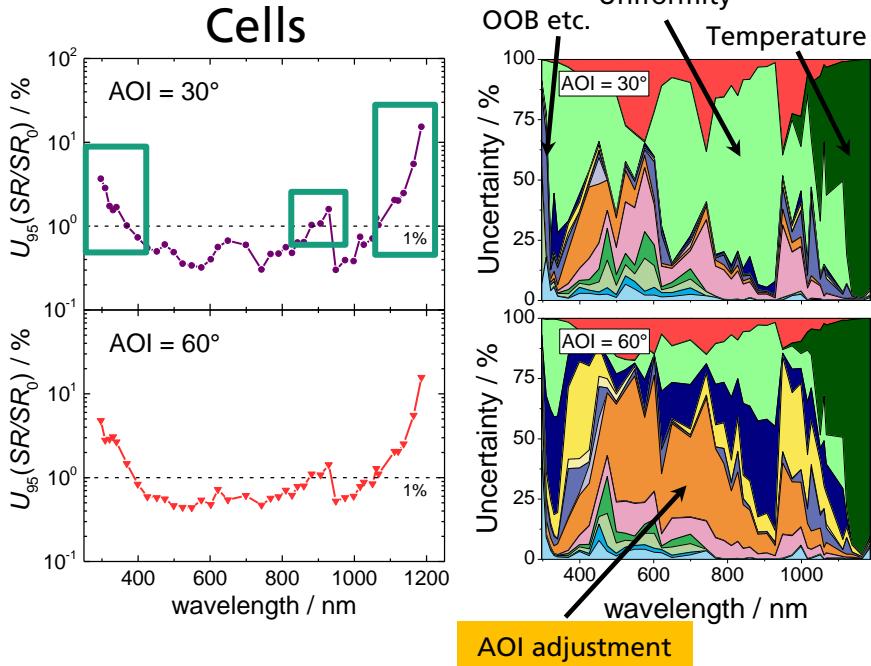
- AOI = 30°: 95% confidence level typically below 1%
- UV: Out-of-band radiation, bandwidth, etc...
- Visible/: Position of sample and NIR associated uniformity correction
- NIR: Temperature



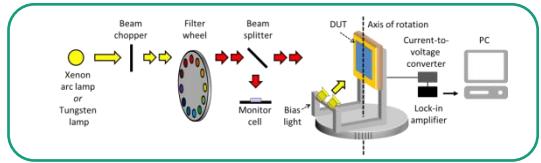
# Change in Angular SR Uncertainty Analysis



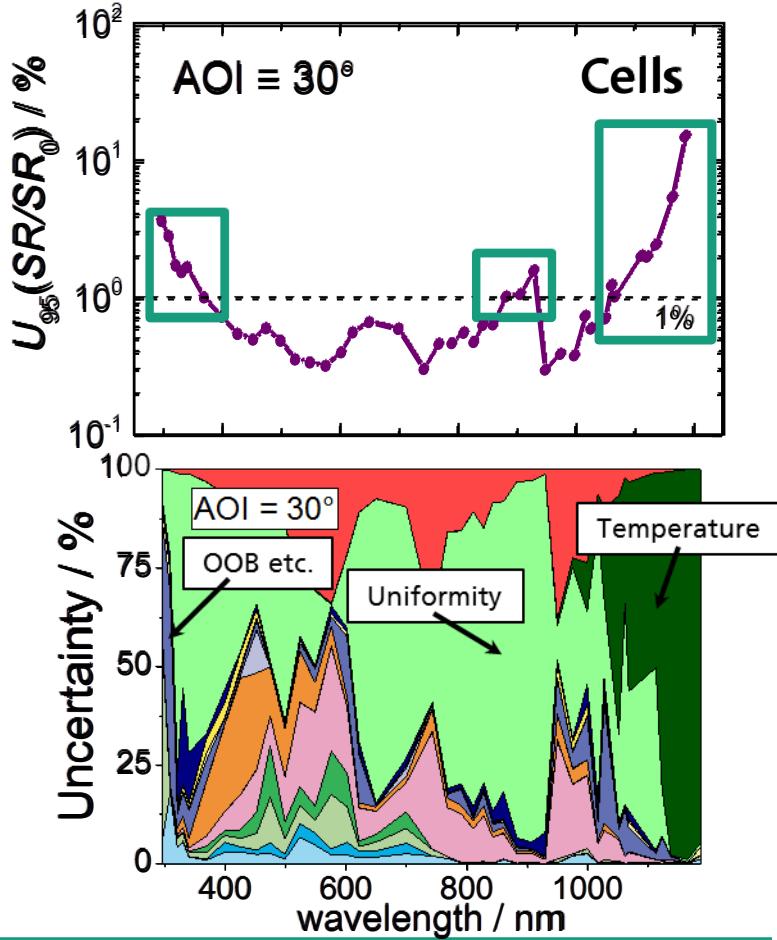
- AOI = 30°: 95% confidence level typically below 1%
  - UV: Out-of-band radiation, bandwidth, etc...
  - Visible/: Position of sample and NIR associated uniformity correction
  - NIR: Temperature
- AOI = 60°: Increasing influence of adjustment of rotating frame (AOI adjustm.)



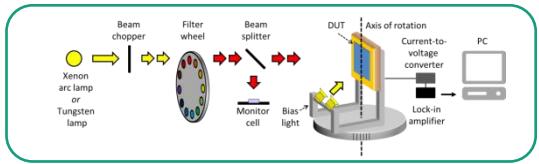
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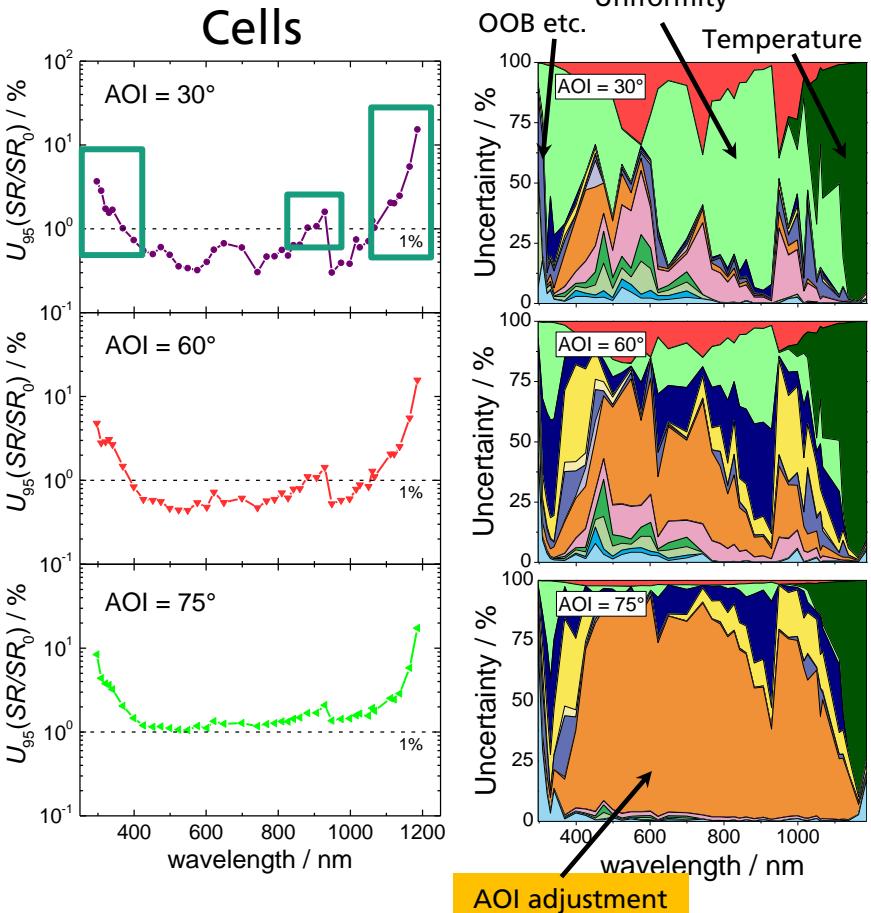
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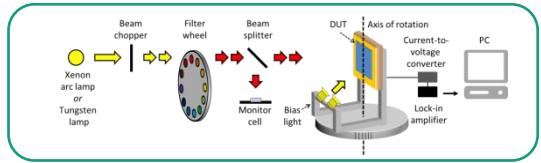
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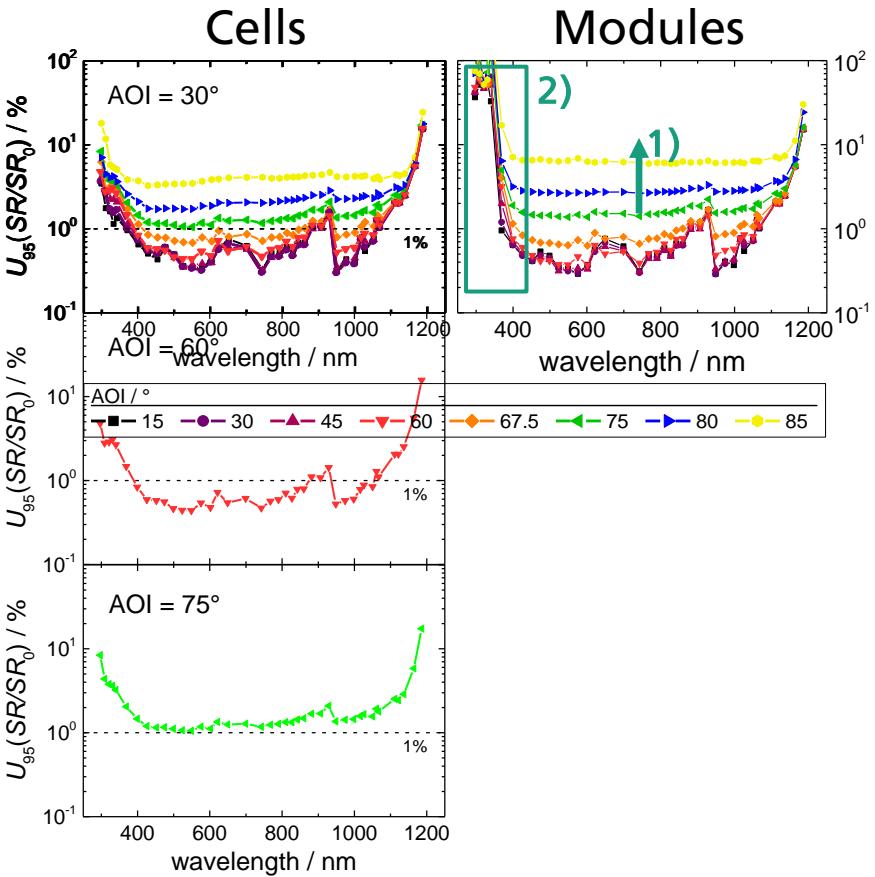
- AOI = 30°: 95% confidence level typically below 1%
  - UV: Out-of-band radiation, bandwidth, etc...
  - Visible/NIR: Position of sample and associated uniformity correction
  - NIR: Temperature
- AOI = 60°: Increasing influence of adjustment of rotating frame (AOI adjustm.)
- AOI = 75°: AOI adjustment dominates



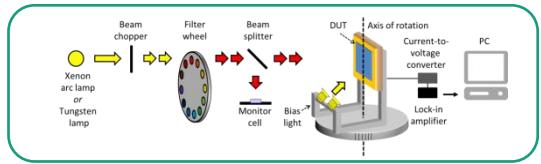
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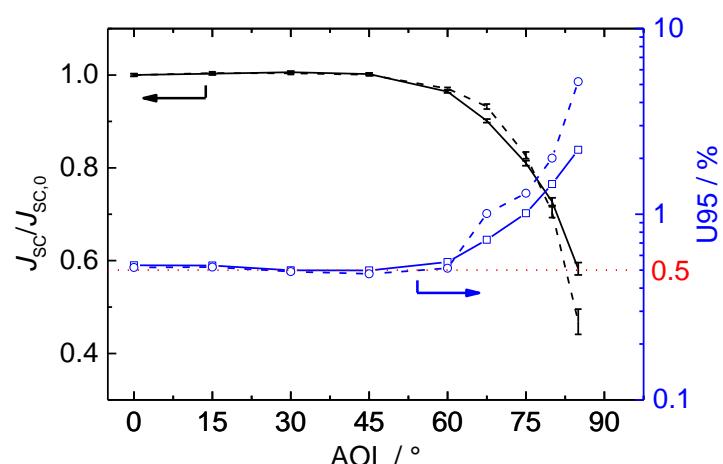
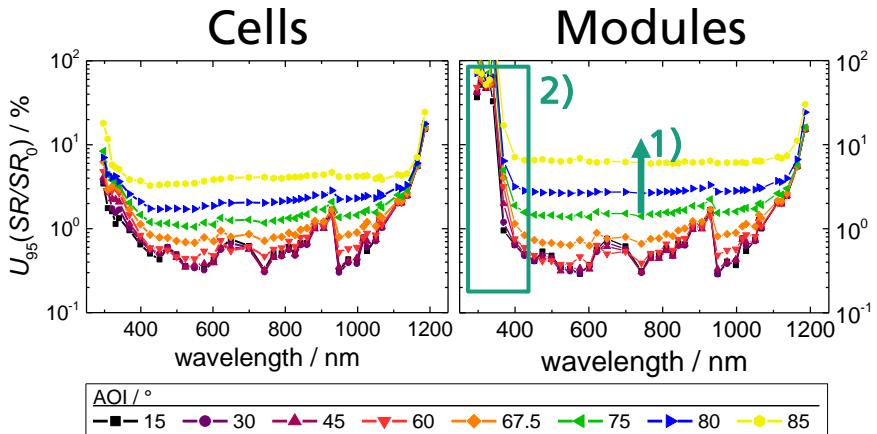
- Differences in measurement uncertainty for cells and modules
  - AOIs > 60°: angle adjustment more critical
  - UV: low signal due to EVA



# Change in Angular SR Uncertainty Analysis



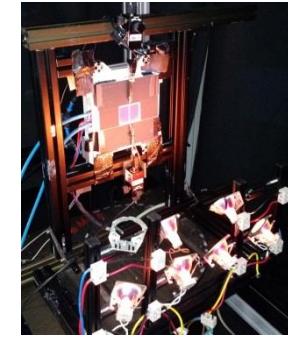
- Differences in measurement uncertainty for cells and modules
  - AOIs > 60°: angle adjustment more critical
  - UV: low signal due to EVA
  
- Change in  $J_{SC}$ :
  - Monte Carlo simulation
  - Random walks for correlations w.r.t wavelength
  
- Lowest measurement uncertainty reported for relative measurement



# Samples

## Cells and Modules

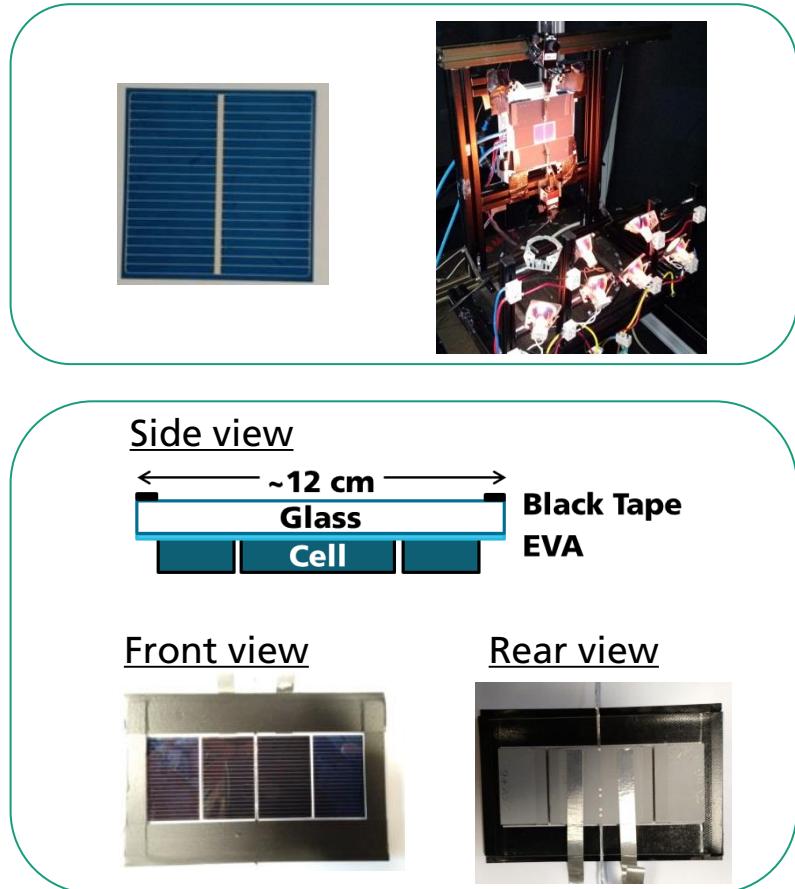
- Six cells
  - Small area  $5 \times 5 \text{ cm}^2$
  - $p$ -type Al-BSF
  - Contacted via micromanipulators with Kelvin probes



# Samples

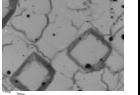
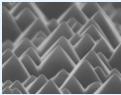
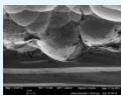
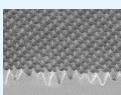
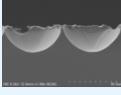
## Cells and Modules

- Six cells
  - Small area  $5 \times 5 \text{ cm}^2$
  - $p$ -type Al-BSF
  - Contacted via micromanipulators with Kelvin probes
- Modules
  - Planar glass
  - Dummy half cells
  - Open rear
    - El. conductive tape
    - Th. conductive gray pad



# Samples

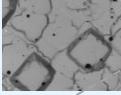
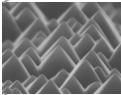
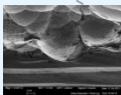
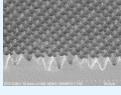
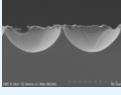
## Front Surface Textures

Texture	Substrate	
PLANAR (chemically polished)	Cz-Si	
RANDOM PYRAMIDS (alkaline-textured)	Cz-Si	
ISOTEXTURE (acidic-textured)	mc-Si	
NIL-HC (nano-imprinted honeycombs) <small>*Volk et al., IEEE JPV 5, 1027-1033, 2015</small>	mc-Si	
LW-HC (laser-structured honeycombs) <small>*Volk et al., 28th EUPVSEC, 1024-1028, 2013</small>	mc-Si	
NANO (shallow nano-textured) <small>*Kafle et al., Solmat 152, 94-102, 2016</small>	mc-Si	

A large optical microscopy image of a textured silicon surface is positioned to the right of the table, with a scale bar indicating 50 µm.

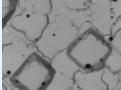
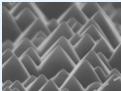
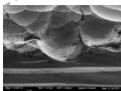
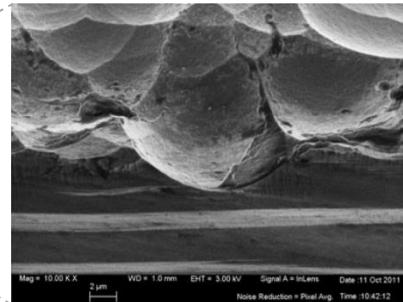
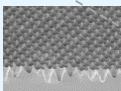
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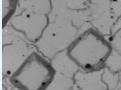
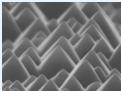
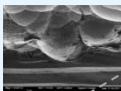
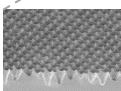
# Samples

## Front Surface Textures

Texture	Substrate	
PLANAR (chemically polished)	Cz-Si	
RANDOM PYRAMIDS (alkaline-textured)	Cz-Si	
ISOTEXTURE (acidic-textured)	mc-Si	  Mag = 10.00 K.X WD = 1.0 mm EHT = 3.00 kV Signal A = InLens Date: 11 Oct 2011 Noise Reduction = Pixel Avg Time: 19:42:12
NIL-HC (nano-imprinted honeycombs) *Volk et al., IEEE JPV 5, 1027-1033, 2015	mc-Si	 
LW-HC (laser-structured honeycombs) *Volk et al., 28th EUPVSEC, 1024-1028, 2013	mc-Si	
NANO (shallow nano-textured) *Kafle et al., Solmat 152, 94-102, 2016	mc-Si	

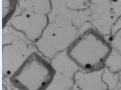
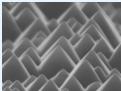
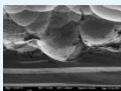
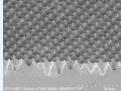
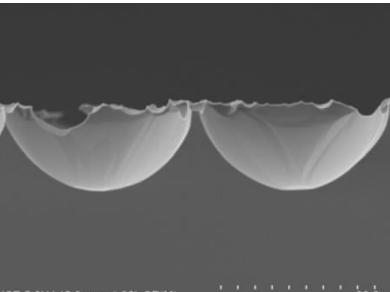
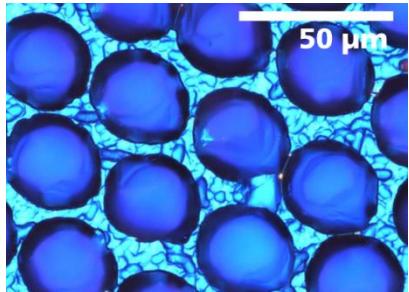
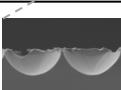
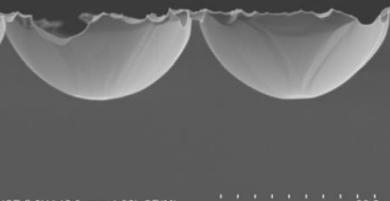
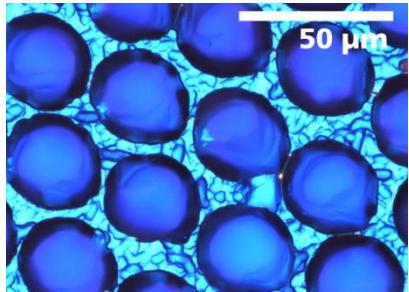
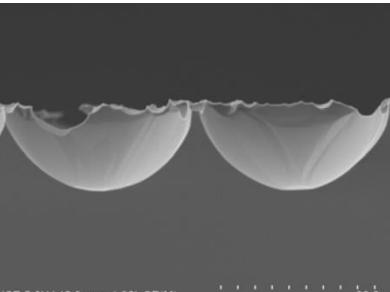
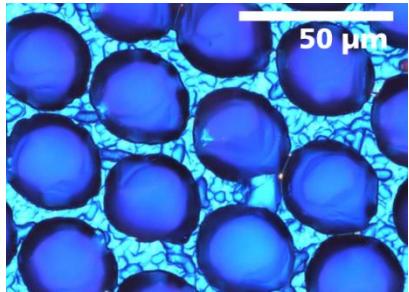
# Samples

## Front Surface Textures

Texture	Substrate	
PLANAR (chemically polished)	Cz-Si	
RANDOM PYRAMIDS (alkaline-textured)	Cz-Si	
ISOTEXTURE (acidic-textured)	mc-Si	 A dashed arrow points from this image to a larger SEM image below showing a wavy surface profile.
NIL-HC (nano-imprinted honeycombs) <small>*Volk et al., IEEE JPV 5, 1027-1033, 2015</small>	mc-Si	 A dashed arrow points from this image to a larger SEM image below showing a wavy surface profile.
LW-HC (laser-structured honeycombs) <small>*Volk et al., 28th EUPVSEC, 1024-1028, 2013</small>	mc-Si	 A dashed arrow points from this image to a larger SEM image below showing a wavy surface profile.
NANO (shallow nano-textured) <small>*Kafle et al., Solmat 152, 94-102, 2016</small>	mc-Si	

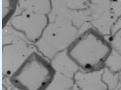
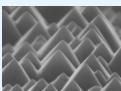
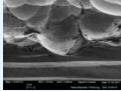
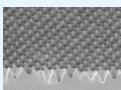
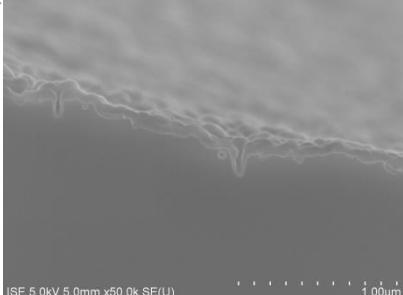
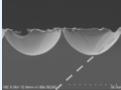
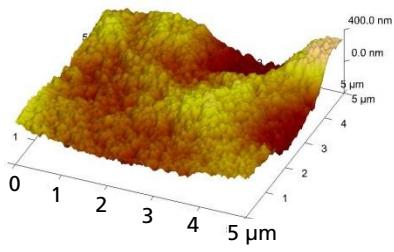
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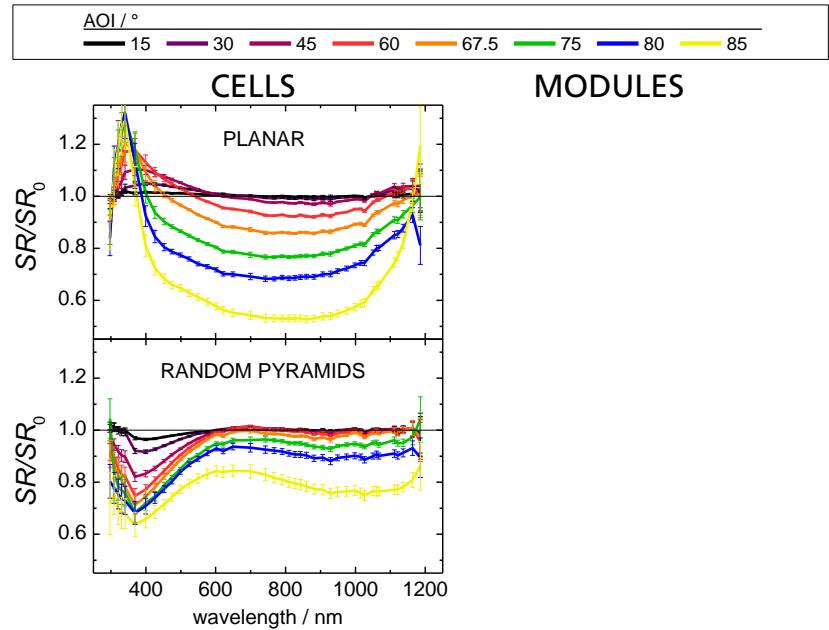
# Samples

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# Results

## Change in Angular SR

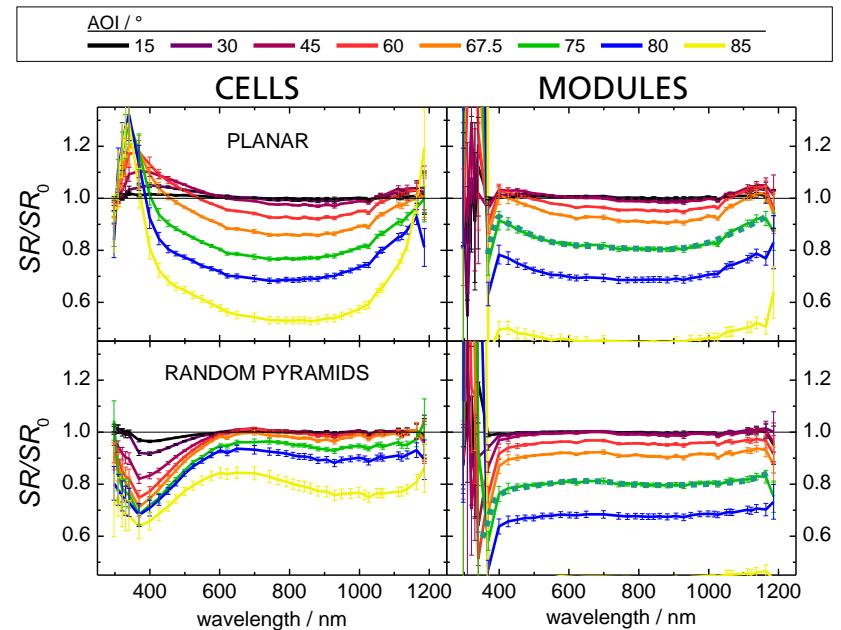


# Results

## Change in Angular SR

### Module level

- More similar characteristics
- Effects of texture still observable



# Results

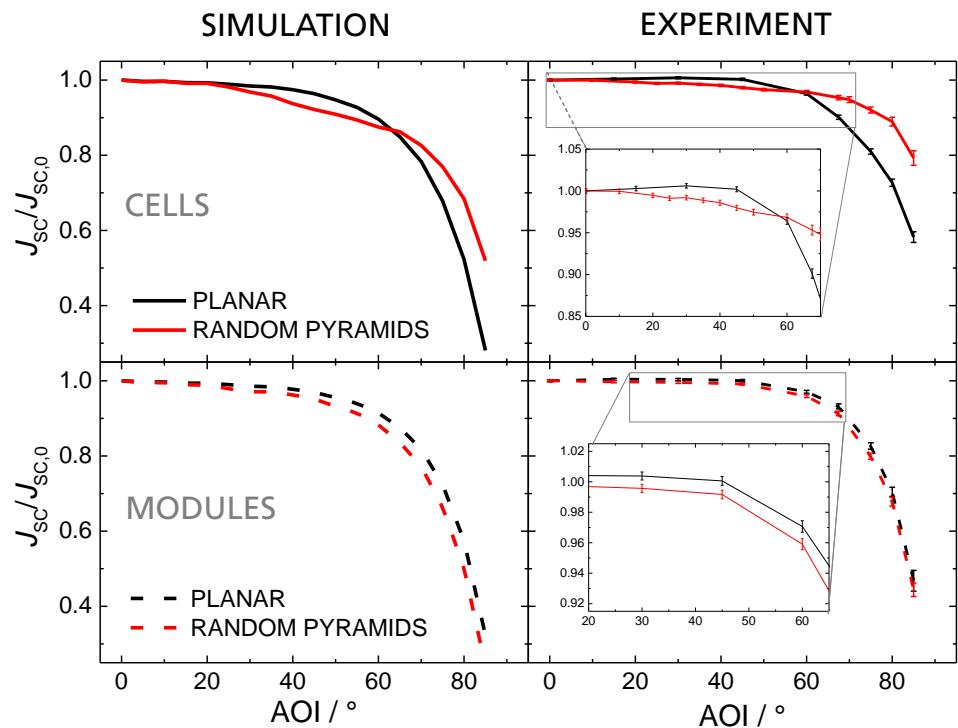
## Change in $J_{sc}$

### Cells

- PLANAR: Stronger decrease for AOI > 60°
- RP: Distinct near-linear decrease for AOI > 15°

### Modules

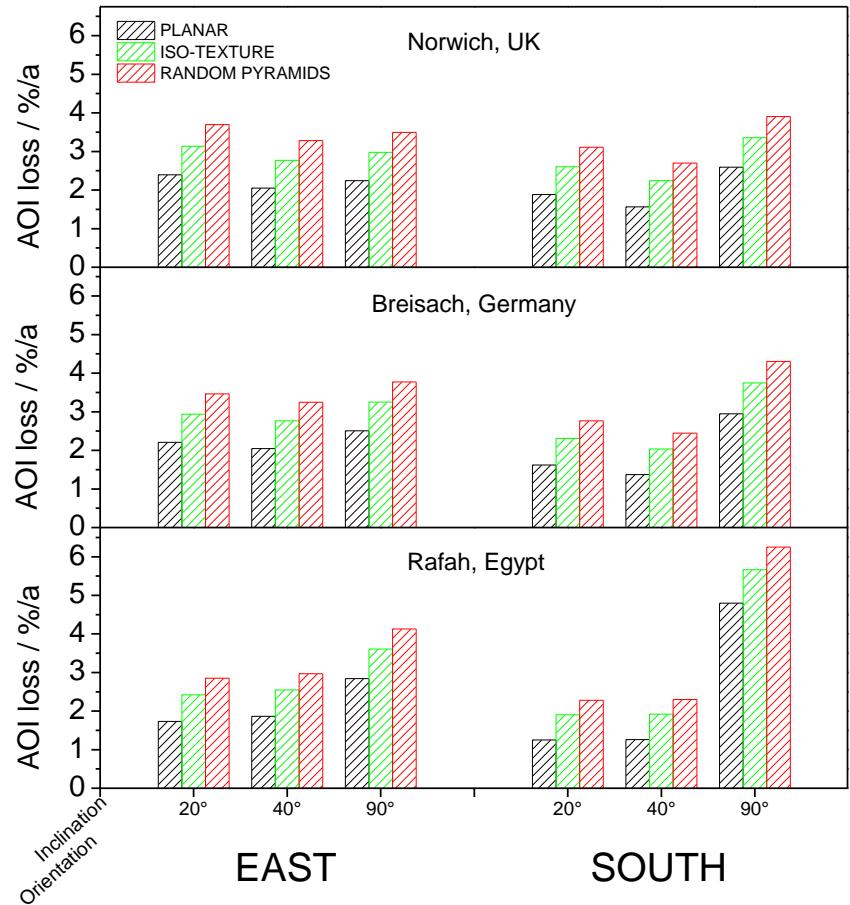
- Differences in the range of 1%
- RP: Stronger AOI dependence



# Energy Rating with Measured Data

## Change in $J_{SC}$

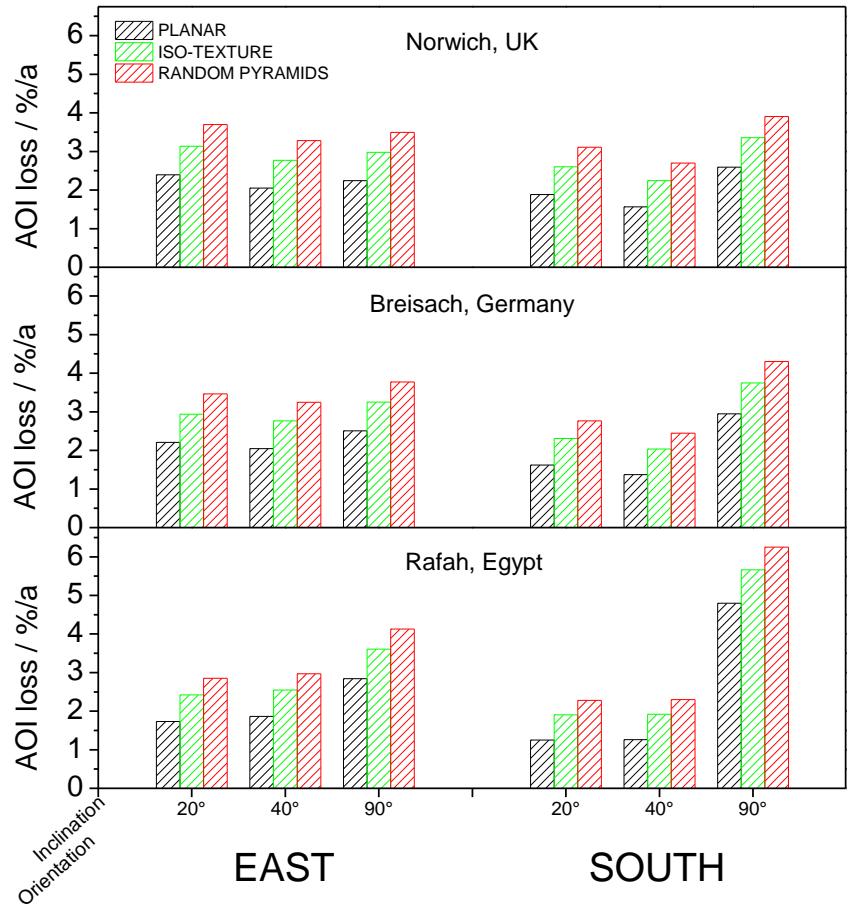
- Three different climate zones
- SolarGIS weather data
  - 10 years
  - 15 min resolution
  - Separated direct and diffuse (AOI 55°) irradiation
- Three module orientations
- Three inclination angles



# Energy Rating with Measured Data

## Change in $J_{SC}$

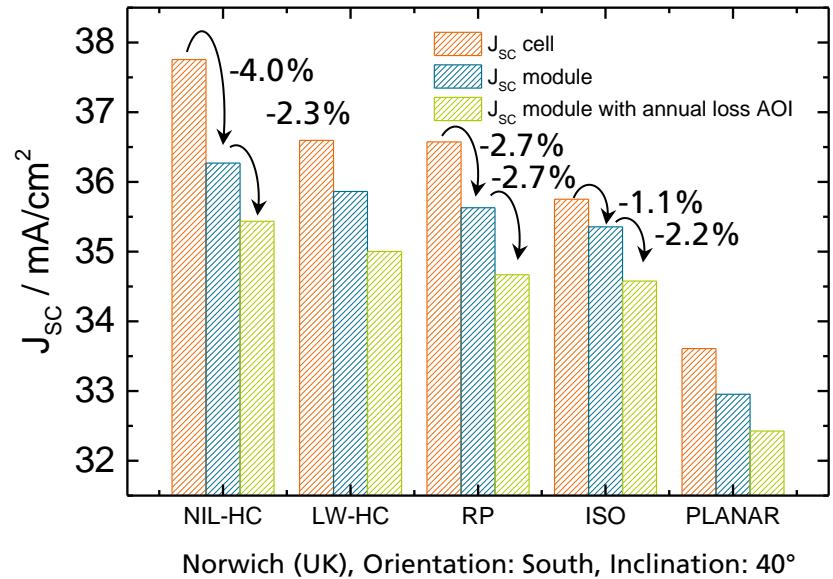
- Typically 2-4 % annual loss due to AOI dependence
- Up to 1.5 % difference due to front texture



# Energy Rating with Measured Data

## Cell-to-Module Losses in $J_{SC}$

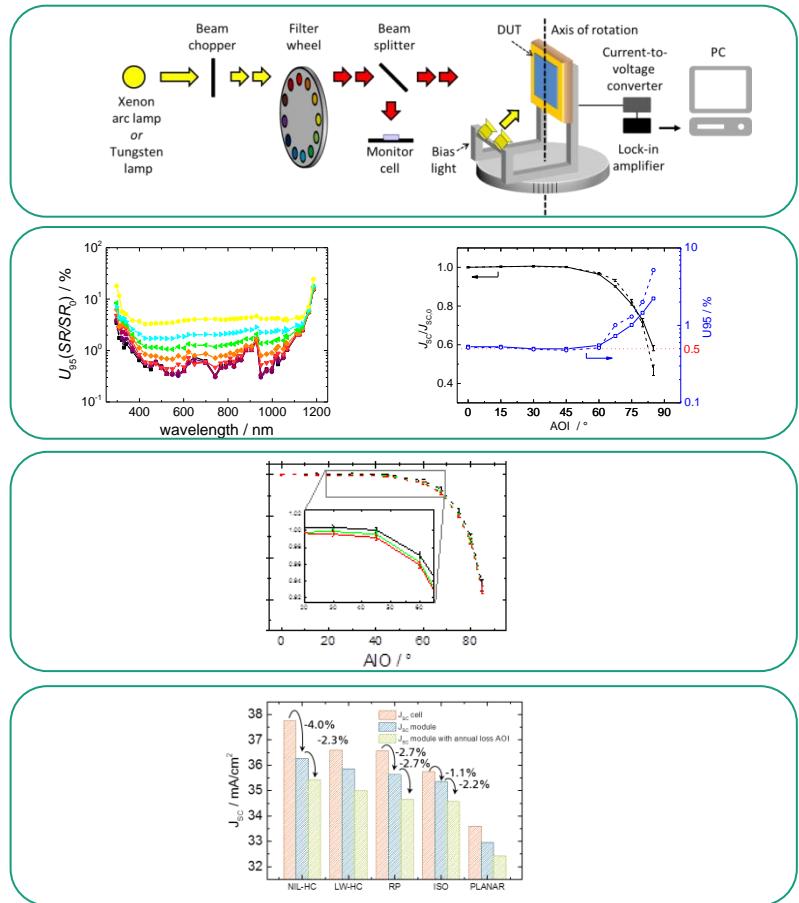
- Convolution of SR with AM1.5g (before and after encapsulation)
- Simulated annual AOI loss (based on measured data)
- Cell-to-module:
  - NIL-HC: -4.0 %
  - RP: -2.7 %
  - ISO: -1.1 %
- AOI losses:
  - RP loses initial advantage over ISO almost completely



Small area laboratory cells  
and mini modules!

# Conclusion

- Measurement setup for angular SR:  
Bias light rotating with the sample
- Uncertainty analysis:  
Change in SR:  $U_{95}(\text{AOI} < 75^\circ) < 1\%$   
Change in  $J_{SC}$ :  $U_{95}(\text{AOI} < 60^\circ) \approx 0.5\%$
- Results for cells and modules:  
Modules: Differences  $\approx 1\%$
- Combination of CTM and AOI losses:  
Random pyramids lose initial advantage over isotexture



## Acknowledgment

# Thank You Very Much for Your Attention!

This work was partly funded by the German Federal Ministry for the Environment, Nature Conservation and Nuclear Safety (Contract Number 0325447 OHM) and the EMRP ENG55 project "Towards an energy-based parameter for photovoltaic classification". The EMRP is jointly funded by the EMRP participating countries within EURAMET and the European Union.

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